

# 8 Mbit (1024K x 8/512K x 16) nvSRAM with Real Time Clock

### **Features**

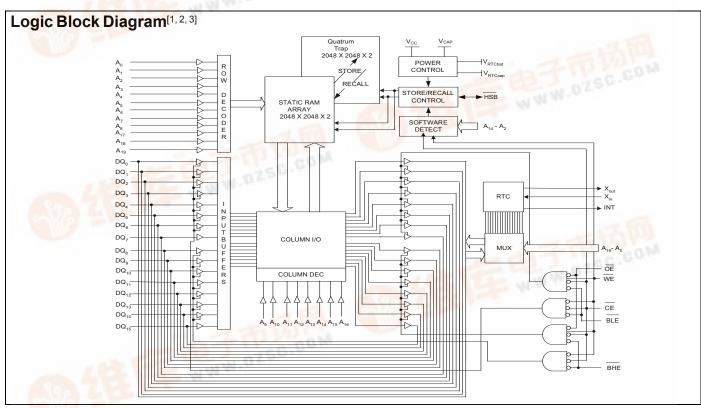
- 20 ns, 25 ns, and 45 ns Access Times
- Internally Organized as 1024K x 8 (CY14B108K) or 512K x 16 (CY14B108M)
- Hands Off Automatic STORE on Power Down with only a Small Capacitor
- STORE to QuantumTrap Nonvolatile Elements is Initiated by Software, Device Pin, or AutoStore on Power Down
- RECALL to SRAM Initiated by Software or Power Up
- High Reliability
- Infinite Read, Write, and RECALL Cycles
- 200,000 STORE Cycles to QuantumTrap
- 20 year Data Retention
- Single 3V +20%, -10% Operation
- Data Integrity of Cypress nvSRAM Combined with Full Featured Real Time Clock (RTC)

- Watchdog Timer
- Clock Alarm with Programmable Interrupts
- Capacitor or Battery Backup for RTC
- Commercial and Industrial Temperatures
- 44 and 54-pin TSOP II Package
- Pb-free and RoHS Compliance

# **Functional Description**

The Cypress CY14B108K/CY14B108M combines a 8-Mbit nonvolatile static RAM with a full featured RTC in a monolithic integrated circuit. The embedded nonvolatile elements incorporate QuantumTrap technology producing the world's most reliable nonvolatile memory. The SRAM is read and written infinite number of times, while independent nonvolatile data resides in the nonvolatile elements.

The RTC function provides an accurate clock with leap year tracking and a programmable, high accuracy oscillator. The alarm function is programmable for periodic minutes, hours, days, or months alarms. There is also a programmable watchdog timer for process control.

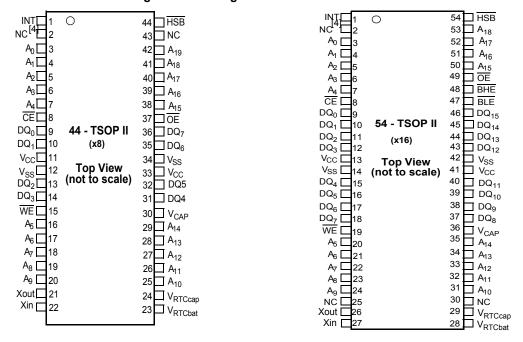


- Address A<sub>0</sub> A<sub>19</sub> for x8 configuration and Address A<sub>0</sub> A<sub>18</sub> for x16 configuration.
   <u>Data</u> DQ<sub>0</sub> DQ<sub>7</sub> for x8 configuration and Data DQ<sub>0</sub> DQ<sub>15</sub> for x16 configuration.
   BHE and BLE are applicable for x16 configuration only.



### **Pinouts**

Figure 1. Pin Diagram: 44-Pln and 54-Pin TSOP II



**Table 1. Pin Definitions** 

Pin Name	I/O Type	Description
A <sub>0</sub> - A <sub>19</sub>	Input	Address Inputs Used to Select one of the 1,048,576 bytes of the nvSRAM for x8 Configuration.
$A_0 - A_{18}$		Address Inputs Used to Select one of the 524,288 words of the nvSRAM for x16 Configuration.
$DQ_0 - DQ_7$	Input/Output	Bidirectional Data I/O Lines for x8 Configuration. Used as input or output lines depending on operation.
DQ <sub>0</sub> – DQ <sub>15</sub>		<b>Bidirectional Data I/O Lines for x16 Configuration</b> . Used as input or output lines depending on operation.
NC	No Connect	No Connects. This pin is not connected to the die.
WE	Input	<b>Write Enable Input, Active LOW</b> . When selected LOW, data on the I/O pins is written to the specific address location.
CE	Input	Chip Enable Input, Active LOW. When LOW, selects the chip. When HIGH, deselects the chip.
ŌE	Input	Output Enable, Active LOW. The active LOW OE input enables the data output buffers during read cycles. Deasserting OE HIGH causes the I/O pins to tristate.
BHE	Input	Byte High Enable, Active LOW. Controls DQ <sub>15</sub> - DQ <sub>8</sub> .
BLE	Input	Byte Low Enable, Active LOW. Controls DQ <sub>7</sub> - DQ <sub>0</sub> .
X <sub>out</sub>	Output	Crystal Connection. Drives crystal on start up.
X <sub>in</sub>	Input	Crystal Connection. For 32.768 KHz crystal.
V <sub>RTCcap</sub>	Power Supply	Capacitor Supplied Backup RTC Supply Voltage. Left unconnected if V <sub>RTCbat</sub> is used.
V <sub>RTCbat</sub>	Power Supply	Battery Supplied Backup RTC Supply Voltage. Left unconnected if V <sub>RTCcap</sub> is used.

#### Note

<sup>4.</sup> Address expansion for 16 Mbit. NC pin not connected to die.



Table 1. Pin Definitions (continued)

Pin Name	I/O Type	Description
INT	Output	Interrupt Output. Programmable to respond to the clock alarm, the watchdog timer, and the power monitor. Also programmable to either active HIGH (push or pull) or LOW (open drain).
V <sub>SS</sub>	Ground	Ground for the Device. Must be connected to ground of the system.
V <sub>CC</sub>	Power Supply	Power Supply Inputs to the Device. 3.0V +20%, -10%.
HSB	Input/Output	Hardware STORE Busy (HSB). When LOW this output indicates that a Hardware STORE is in progress. When pulled LOW external to the chip it initiates a nonvolatile STORE operation. A weak internal pull up resistor keeps this pin HIGH if not connected (connection optional). After each STORE operation HSB is driven HIGH for short time with standard output high current.
V <sub>CAP</sub>	Power Supply	<b>AutoStore Capacitor</b> . Supplies power to the nvSRAM during power loss to store data from SRAM to nonvolatile elements.

### **Device Operation**

The CY14B108K/CY14B108M nvSRAM is made up of two functional components paired in the same physical cell. These are a SRAM memory cell and a nonvolatile QuantumTrap cell. The SRAM memory cell operates as a standard fast static RAM. Data in the SRAM is transferred to the nonvolatile cell (the STORE operation), or from the nonvolatile cell to the SRAM (the RECALL operation). Using this unique architecture, all cells are stored and recalled in parallel. During the STORE and RECALL operations SRAM read and write operations are inhibited. The CY14B108K/CY14B108M supports infinite reads and writes similar to a typical SRAM. In addition, it provides infinite RECALL operations from the nonvolatile cells and up to 200K STORE operations. See the Truth Table For SRAM Operations on page 24 for a complete description of read and write modes.

#### SRAM Read

The CY14B108K/CY14B108M performs a read cycle whenever CE and OE are LOW, and WE and HSB are HIGH. The address specified on pins  $A_{0-19}$  or  $A_{0-18}$  determines which of the 1,048,576 data bytes or 524,288 words of 16 bits each are accessed. Byte enables (BHE, BLE) determine which bytes are enabled to the output, in the case of 16-bit words. When the read is initiated by an address transition, the outputs are valid after a delay of  $t_{AA}$  (read cycle 1). If the read is initiated by CE or OE, the outputs are valid at  $t_{ACE}$  or at  $t_{DOE}$ , whichever is later (read cycle 2). The data output repeatedly responds to address changes within the  $t_{AA}$  access time without the need for transitions on any control input pins. This remains valid until another address change or until CE or OE is brought HIGH, or WE or HSB is brought LOW.

## **SRAM Write**

A write cycle is performed when  $\overline{\text{CE}}$  and  $\overline{\text{WE}}$  are LOW and  $\overline{\text{HSB}}$  is HIGH. The address inputs must be stable before entering the write cycle and must remain stable until  $\overline{\text{CE}}$  or  $\overline{\text{WE}}$  goes HIGH at the end of the cycle. The data on the common I/O pins DO<sub>0-15</sub> are written into the memory if it is valid  $t_{SD}$  before the end of a  $\overline{\text{WE}}$  controlled write or before the end of a  $\overline{\text{CE}}$  controlled write. The Byte Enable inputs (BHE, BLE) determine which bytes are written, in the case of 16-bit words. Keep  $\overline{\text{OE}}$  HIGH during the entire write cycle to avoid data bus contention on common I/O lines. If  $\overline{\text{OE}}$  is left  $\underline{\text{LOW}}$ , internal circuitry turns off the output buffers  $t_{\text{HZWE}}$  after  $\overline{\text{WE}}$  goes LOW.

# **AutoStore Operation**

The CY14B108K/CY14B108M stores data to the nvSRAM using one of three storage operations. The<u>se</u> three operations are: Hardware STORE, activated by the HSB; Software STORE, activated by an address sequence; AutoStore, on device power down. The AutoStore operation is a unique feature of QuantumTrap technology and is enabled by default on the CY14B108K/CY14B108M.

During normal operation, the device draws current from  $V_{CC}$  to charge a capacitor connected to the  $V_{CAP}$  pin. This stored charge is used by the chip to perform a single STORE operation. If the voltage on the  $V_{CC}$  pin drops below  $V_{SWITCH}$ , the part automatically disconnects the  $V_{CAP}$  pin from  $V_{CC}$ . A STORE operation is initiated with power provided by the  $V_{CAP}$  capacitor.

**Note** If the capacitor is not connected to  $V_{CAP}$  pin, AutoStore must be disabled using the soft sequence specified in Preventing AutoStore on page 5. In case AutoStore is enabled without a capacitor on  $V_{CAP}$  pin, the device attempts an AutoStore operation without sufficient charge to complete the Store. This may corrupt the data stored in nvSRAM.

Figure 2. AutoStore Mode

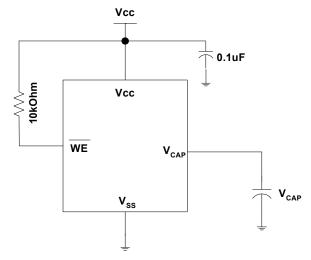


Figure 2 shows the proper connection of the storage capacitor ( $V_{CAP}$ ) for automatic STORE operation. Refer to DC Electrical Characteristics on page 15 for the size of the  $V_{CAP}$ . The voltage



on the  $V_{CAP}$  pin is driven to  $V_{CC}$  by a regulator on the chip. A pull up should be placed on  $\overline{WE}$  to hold it inactive during power up. This pull up is only effective if the  $\overline{WE}$  signal is tristate during power up. Many MPUs tristate their controls on power up. Verify this when using the pull up. When the nvSRAM comes out of power-on-recall, the MPU must be active or the  $\overline{WE}$  held inactive until the MPU comes out of reset.

To reduce unnecessary nonvolatile STOREs, AutoStore, and Hardware STORE operations are ignored unless at least one write operation has taken place since the most recent STORE or RECALL cycle. Software initiated STORE cycles are performed regardless of whether a write operation has taken place. The HSB signal is monitored by the system to detect if an AutoStore cycle is in progress.

# Hardware STORE (HSB) Operation

The CY14B108K/CY14B108M provides the  $\overline{\text{HSB}}$  pin to control and acknowledge the STORE operations. The  $\overline{\text{HSB}}$  pin is used to request a Hardware STORE cycle. When the HSB pin is driven LOW, the CY14B108K/CY14B108M conditionally initiates a STORE operation after  $t_{DELAY}$ . An actual STORE cycle begins only if a write to the SRAM has taken place since the last STORE or RECALL cycle. The HSB pin also acts as an open drain driver that is internally driven LOW to indicate a busy condition when the STORE (initiated by any means) is in progress.

SRAM write operations that are in progress when  $\overline{\text{HSB}}$  is driven LOW by any means are given time ( $t_{\text{DELAY}}$ ) to complete before the STORE operation <u>is initiated</u>. However, any SRAM <u>write</u> cycles requested after  $\overline{\text{HSB}}$  goes LOW are in<u>hibited</u> until  $\overline{\text{HSB}}$  returns HIGH. In case the write latch is not set,  $\overline{\text{HSB}}$  is not driven LOW by the CY14B108K/CY14B108M. But any SRAM read and write cycles are inhibited until  $\overline{\text{HSB}}$  is returned HIGH by MPU or other external source.

During any STORE operation, regardless of how it is <a href="initial">initial</a>ted, the CY14B108K/CY14B108M continues to drive the HSB pin LOW, releasing it only when the STORE is complete. Upon completion of the STORE operation, the CY14B108K/CY14B108M remains disabled until the HSB pin returns HIGH. Leave the HSB unconnected if it is not used.

# Hardware RECALL (Power Up)

During power up or after any low power condition ( $V_{CC}$ <  $V_{SWITCH}$ ), an internal RECALL request is latched. When  $V_{CC}$  again exceeds the  $V_{SWITCH}$  on powerup, a RECALL cycle is automatically initiated and takes  $t_{HRECALL}$  to complete. During this time, the HSB pin is driven LOW by the HSB driver and all reads and writes to nvSRAM are inhibited.

#### Software STORE

Data is transferred from the SRAM to the nonvolatile memory by a software address sequence. The CY14B108K/CY14B108M Software STORE cycle is initiated by executing sequential CE or OE controlled read cycles from six specific address locations in exact order. During the STORE cycle, an erase of the previous nonvolatile data is first performed, followed by a program of the nonvolatile elements. After a STORE cycle is initiated, further input and output are disabled until the cycle is completed.

Because a sequence of reads from specific addresses is used for STORE initiation, it is important that no other read or write accesses intervene in the sequence, or the sequence is aborted and no STORE or RECALL takes place.

To initiate the Software STORE cycle, the following read sequence must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x8FC0 Initiate STORE cycle

The software sequence may be clocked with CE controlled reads or OE controlled reads, with WE kept HIGH for all the six READ sequences. After the sixth address in the sequence is entered, the STORE cycle commences and the chip is disabled. HSB is driven LOW. After the t<sub>STORE</sub> cycle time is fulfilled, the SRAM is activated again for the read and write operation.

### Software RECALL

Data is transferred from the nonvolatile memory to the SRAM by a software address sequence. A software RECALL cycle is initiated with a sequence of read operations in a manner similar to the Software STORE initiation. To initiate the RECALL cycle, perform the following sequence of CE or OE controlled read operations:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- Read address 0x4C63 Initiate RECALL cycle

Internally, RECALL is a two step procedure. First, the SRAM data is cleared; then, the nonvolatile information is transferred into the SRAM cells. After the  $t_{RECALL}$  cycle time, the SRAM is again ready for read and write operations. The RECALL operation does not alter the data in the nonvolatile elements.



Table 2. Mode Selection

CE	WE	OE, BHE, BLE <sup>[3]</sup>	A <sub>15</sub> - A <sub>0</sub> <sup>[5]</sup>	Mode	I/O	Power
Н	X	X	X	Not Selected	Output High Z	Standby
L	Н	L	Х	Read SRAM	Output Data	Active
L	L	X	X	Write SRAM	Input Data	Active
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8B45	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM AutoStore Disable	Output Data	Active <sup>[6]</sup>
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4B46	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM AutoStore Enable	Output Data	Active <sup>[6]</sup>
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8FC0	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile STORE	Output Data Output Data Output Data Output Data Output Data Output Data Output High Z	Active I <sub>CC2</sub> <sup>[6]</sup>
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4C63	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile RECALL	Output Data Output Data Output Data Output Data Output Data Output Data Output High Z	Active <sup>[6]</sup>

# **Preventing AutoStore**

The AutoStore function is disabled by initiating an AutoStore disable sequence. A sequence of read operations is performed in a manner similar to the Software STORE initiation. To initiate the AutoStore disable sequence, the following sequence of CE or OE controlled read operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x8B45 AutoStore Disable

AutoStore is re-enabled by initiating an AutoStore enable sequence. A sequence of read operations is performed in a manner similar to the software RECALL initiation. To initiate the AutoStore enable sequence, the following sequence of CE or OE controlled read operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x4B46 AutoStore Enable

If the AutoStore function is disabled or re-enabled, a manual STORE operation (hardware or software) issued to save the AutoStore state through subsequent power down cycles. The part comes from the factory with AutoStore enabled.

#### Notes

- While there are 20 address lines on the CY14B108K (19 address lines on the CY14B108M), only the 13 address lines (A<sub>14</sub> A<sub>2</sub>) are used to control software modes.
   The remaining address lines are don't care.
- 6. The six consecutive address locations must be in the order listed. WE must be HIGH during all six cycles to enable a nonvolatile cycle.



### **Data Protection**

The CY14B108K/CY14B108M protects data from corruption during low voltage conditions by inhibiting all externally initiated STORE and write operations. The low voltage condition is detected when  $V_{\rm CC}$  is less than  $V_{\rm SWITCH}$ . If the CY14B108K/CY14B108M is in a write mode (both CE and WE are LOW) at power up, after a RECALL or STORE, the write is inhibited until the SRAM is enabled after  $t_{\rm LZHSB}$  (HSB to output active). This protects against inadvertent writes during power up or brown out conditions.

### **Noise Considerations**

Refer to CY application note AN1064.

### **Best Practices**

nvSRAM products have been used effectively for over 15 years. While ease-of-use is one of the product's main system values, experience gained working with hundreds of applications has resulted in the following suggestions as best practices:

■ The nonvolatile cells in this nvSRAM product are delivered from Cypress with 0x00 written in all cells. Incoming inspection routines at customer or contract manufacturer's sites sometimes reprogram these values. Final NV patterns are typically repeating patterns of AA, 55, 00, FF, A5, or 5A. End product's firmware should not assume an NV array is in a set programmed state. Routines that check memory content values to determine first time system configuration, cold or warm boot status, and so on should always program a unique NV pattern (that is, complex 4-byte pattern of 46 E6 49 53 hex or more random bytes) as part of the final system manufacturing test to ensure these system routines work consistently.

- Power up boot firmware routines should rewrite the nvSRAM into the desired state (for example, autostore enabled). While the nvSRAM is shipped in a preset state, best practice is to again rewrite the nvSRAM into the desired state as a safeguard against events that might flip the bit inadvertently such as program bugs and incoming inspection routines.
- The V<sub>CAP</sub> value specified in this data sheet includes a minimum and a maximum value size. Best practice is to meet this requirement and not exceed the maximum V<sub>CAP</sub> value because the nvSRAM internal algorithm calculates V<sub>CAP</sub> charge and discharge time based on this maximum V<sub>CAP</sub> value. Customers that want to use a larger V<sub>CAP</sub> value to make sure there is extra store charge and store time should discuss their V<sub>CAP</sub> size selection with Cypress to understand any impact on the V<sub>CAP</sub> voltage level at the end of a t<sub>RECALL</sub> period.



### **Real Time Clock Operation**

### nvTime Operation

The CY14B108K/CY14B108M offers internal registers that contain clock, alarm, watchdog, interrupt, and control functions. RTC registers use the last 16 address locations of the SRAM. Internal double buffering of the clock and timer information registers prevents accessing transitional internal clock data during a read or write operation. Double buffering also circumvents disrupting normal timing counts or the clock accuracy of the internal clock when accessing clock data. Clock and alarm registers store data in BCD format.

RTC functionality is described with respect to CY14B108K in the following sections. The same description applies to CY14B108M, except for the RTC register addresses. The RTC register addresses for CY14B108K range from 0xFFFF0 to 0xFFFFF, while those for CY14B108M range from 0x7FFF0 to 0x7FFFF. Refer to Table 4 on page 11 and Table 5 on page 12 for a detailed Register Map description.

### **Clock Operations**

The clock registers maintain time up to 9,999 years in one second increments. The time can be set to any calendar time and the clock automatically keeps track of days of the week and month, leap years, and century transitions. There are eight registers dedicated to the clock functions, which are used to set time with a write cycle and to read time during a read cycle. These registers contain the time of day in BCD format. Bits defined as '0' are currently not used and are reserved for future use by Cypress.

### Reading the Clock

The double buffered RTC register structure reduces the chance of reading incorrect data from the clock. The user must stop internal updates to the CY14B108K time keeping registers before reading clock data, to prevent reading of data in transition. Stopping the register updates does not affect clock accuracy.

The updating process is stopped by writing a '1' to the read bit 'R' (in the flags register at 0xFFFF0), and does not restart until a '0' is written to the read bit. The RTC registers are then read while the internal clock continues to run. After a '0' is written to the read bit ('R'), all RTC registers are simultaneously updated within 20 ms

#### **Setting the Clock**

Setting the write bit 'W' (in the flags register at 0xFFFF0) to a '1' stops updates to the time keeping registers and enables the time to be set. The correct day, date, and time is then written into the registers and must be in 24 hour BCD format. The time written is referred to as the "Base Time". This value is stored in nonvolatile registers and used in the calculation of the current time. Resetting the write bit to '0' transfers the values of timekeeping registers to the actual clock counters, after which the clock resumes normal operation.

If the time written to the timekeeping registers is not in the correct BCD format, each invalid nibble of the RTC registers continue counting to 0xF before rolling over to 0x0 after which RTC resumes normal operation.

Note The values entered in the timekeeping, alarm, calibration, and interrupt registers need a STORE operation to be saved in

nonvolatile memory. Therefore, while working in AutoStore disabled mode, the user must perform a STORE operation after writing into the RTC registers for the RTC to work correctly.

### **Backup Power**

The RTC in the CY14B108K is intended for permanently powered operation. The  $V_{RTCcap}$  or  $V_{RTCbat}$  pin is connected depending on whether a capacitor or battery is chosen for the application. When the primary power,  $V_{CC}$ , fails and drops below  $V_{SWITCH}$  the device switches to the backup power supply.

The clock oscillator uses very little current, which maximizes the backup time available from the backup source. Regardless of the clock operation with the primary source removed, the data stored in the nvSRAM is secure, having been stored in the nonvolatile elements when power was lost.

During backup operation, the CY14B108K consumes a maximum of 300 nanoamps at room temperature. User must choose capacitor or battery values according to the application.

Backup time values based on maximum current specifications are shown in the following table. Nominal backup times are approximately two times longer.

Table 3. RTC Backup Time

Capacitor Value	Backup Time
0.1F	72 hours
0.47F	14 days
1.0F	30 days

Using a capacitor has the obvious advantage of recharging the backup source each time the system is powered up. If a battery is used, a 3V lithium is recommended and the CY14B108K sources current only from the battery when the primary power is removed. However, the battery is not recharged at any time by the CY14B108K. The battery capacity must be chosen for total anticipated cumulative down time required over the life of the system.

### Stopping and Starting the Oscillator

The OSCEN bit in the calibration register at 0xFFFF8 controls the enable and disable of the oscillator. This bit is nonvolatile and is shipped to customers in the "enabled" (set to 0) state. To preserve the battery life when the system is in storage, OSCEN must be set to '1'. This turns off the oscillator circuit, extending the battery life. If the OSCEN bit goes from disabled to enabled, it takes approximately one second (two seconds maximum) for the oscillator to start.

While system power is off, If the voltage on the backup supply ( $V_{RTCcap}$  or  $V_{RTCbat}$ ) falls below their respective minimum level, the oscillator may fail. The CY14B108K has the ability to detect oscillator failure when system power is restored. This is recorded in the OSCF (Oscillator Failed bit) of the flags register at the address 0xFFFF0. When the device is powered on ( $V_{CC}$  goes above  $V_{SWITCH}$ ) the OSCEN bit is checked for "enabled" status. If the OSCEN bit is enabled and the oscillator is not active within the first 5 ms, the OSCF bit is set to "1". The system must check for this condition and then write '0' to clear the flag. Note that in addition to setting the OSCF flag bit, the time registers are reset to the "Base Time" (see Setting the Clock on page 7), which is the value last written to the timekeeping registers. The control or



calibration registers and the OSCEN bit are not affected by the 'oscillator failed' condition.

The value of OSCF must be reset to '0' when the time registers are written for the first time. This initializes the state of this bit which may have become set when the system was first powered on.

To reset OSCF, set the write bit "W" (in the Flags register at 0xFFFF0) to a "1" to enable writes to the Flag register. Write a "0" to the OSCF bit and then reset the write bit to "0" to disable writes.

#### Calibrating the Clock

The RTC is driven by a quartz controlled crystal with a nominal frequency of 32.768 kHz. Clock accuracy depends on the quality of the crystal and calibration. The crystals available in market typically have an error of  $\pm 20$  ppm to  $\pm 35$  ppm. However, CY14B108K employs a calibration circuit that improves the accuracy to  $\pm 1/-2$  ppm at 25°C. This implies an error of  $\pm 2.5$  seconds to  $\pm 3$ 0 seconds per month.

The calibration circuit adds or subtracts counts from the oscillator divider circuit to achieve this accuracy. The number of pulses that are suppressed (subtracted, negative calibration) or split (added, positive calibration) depends upon the value loaded into the five calibration bits found in Calibration register at 0xFFFF8. The calibration bits occupy the five lower order bits in the Calibration register. These bits are set to represent any value between '0' and 31 in binary form. Bit D5 is a sign bit, where a '1' indicates positive calibration and a '0' indicates negative calibration. Adding counts speeds the clock up and subtracting counts slows the clock down. If a binary '1' is loaded into the register, it corresponds to an adjustment of 4.068 or –2.034 ppm offset in oscillator error, depending on the sign.

Calibration occurs within a 64-minute cycle. The first 62 minutes in the cycle may, once every minute, have one second shortened by 128 or lengthened by 256 oscillator cycles. If a binary '1' is loaded into the register, only the first two minutes of the 64-minute cycle are modified. If a binary 6 is loaded, the first 12 are affected, and so on. Therefore, each calibration step has the effect of adding 512 or subtracting 256 oscillator cycles for every 125,829,120 actual oscillator cycles, that is, 4.068 or –2.034 ppm of adjustment per calibration step in the Calibration register.

To determine the required calibration, the CAL bit in the Flags register (0xFFFF0) must be set to '1'. This causes the INT pin to toggle at a nominal frequency of 512 Hz. Any deviation measured from the 512 Hz indicates the degree and direction of the required correction. For example, a reading of 512.01024 Hz indicates a +20 ppm error. Hence, a decimal value of -10 (001010b) must be loaded into the Calibration register to offset this error

**Note** Setting or changing the Calibration register does not affect the test output frequency.

To set or clear CAL, set the write bit "W" (in the flags register at 0xFFFF0) to "1" to enable writes to the Flag register. Write a value to CAL, and then reset the write bit to "0" to disable writes.

#### **Alarm**

The alarm function compares user programmed values of alarm time and date (stored in the registers 0xFFFF1-5) with the corresponding time of day and date values. When a match occurs, the

alarm internal flag (AF) is set and an interrupt is generated on INT pin if Alarm Interrupt Enable (AIE) bit is set.

There are four alarm match fields - date, hours, minutes, and seconds. Each of these fields has a match bit that is used to determine if the field is used in the alarm match logic. Setting the match bit to '0' indicates that the corresponding field is used in the match process. Depending on the match bits, the alarm occurs as specifically as once a month or as frequently as once every minute. Selecting none of the match bits (all 1s) indicates that no match is required and therefore, alarm is disabled. Selecting all match bits (all 0s) causes an exact time and date match.

There are two ways to detect an alarm event: by reading the AF flag or monitoring the INT pin. The AF flag in the flags register at 0xFFFF0 indicates that a date or time match has occurred. The AF bit is set to "1" when a match occurs. Reading the flags register clears the alarm flag bit (and all others). A hardware interrupt pin may also be used to detect an alarm event.

To set, clear or enable an alarm, set the 'W' bit (in Flags Register - 0xFFFF0) to '1' to enable writes to Alarm Registers. After writing the alarm value, clear the 'W' bit back to "0" for the changes to take effect.

**Note** CY14B108K requires the alarm match bit for seconds (0xFFFF2 - D7) to be set to '0' for proper operation of Alarm Flag and Interrupt.

### Watchdog Timer

The Watchdog Timer is a free running down counter that uses the 32 Hz clock (31.25 ms) derived from the crystal oscillator. The oscillator must be running for the watchdog to function. It begins counting down from the value loaded in the Watchdog Timer register.

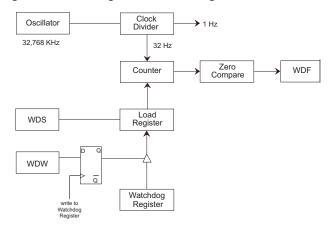
The timer consists of a loadable register and a free running counter. On power up, the watchdog time out value in register 0xFFFF7 is loaded into the Counter Load register. Counting begins on power up and restarts from the loadable value any time the Watchdog Strobe (WDS) bit is set to '1'. The counter is compared to the terminal value of '0'. If the counter reaches this value, it causes an internal flag and an optional interrupt output. You can prevent the time out interrupt by setting WDS bit to '1' prior to the counter reaching '0'. This causes the counter to reload with the watchdog time out value and to be restarted. As long as the user sets the WDS bit prior to the counter reaching the terminal value, the interrupt and WDT flag never occur.

New time out values are written by setting the watchdog write bit to '0'. When the WDW is '0', new writes to the watchdog time out value bits D5-D0 are enabled to modify the time out value. When WDW is '1', writes to bits D5-D0 are ignored. The WDW function enables a user to set the WDS bit without concern that the watchdog timer value is modified. A logical diagram of the watchdog timer is shown in Figure 3. Note that setting the watchdog time out value to '0' disables the watchdog function.

The output of the watchdog timer is the flag bit WDF that is set if the watchdog is allowed to time out. If the Watchdog Interrupt Enable (WIE) bit in the Interrupt register is set, a hardware interrupt on INT pin is also generated on watchdog timeout. The flag and the hardware interrupt are both cleared when user reads the Flags registers.



Figure 3. Watchdog Timer Block Diagram



#### **Power Monitor**

The CY14B108K provides a power management scheme with power fail interrupt capability. It also controls the internal switch to backup power for the clock and protects the memory from low  $V_{CC}$  access. The power monitor is based on an internal band gap reference circuit that compares the  $V_{CC}$  voltage to  $V_{SWITCH}$  threshold.

As described in the section AutoStore Operation on page 3, when  $V_{SWITCH}$  is reached as  $V_{CC}$  decays from power loss, a data STORE operation is initiated from SRAM to the nonvolatile elements, securing the last SRAM data state. Power is also switched from  $V_{CC}$  to the backup supply (battery or capacitor) to operate the RTC oscillator.

When operating from the backup source, read and write operations to nvSRAM are inhibited and the clock functions are not available to the user. The clock continues to operate in the background. The updated clock data is available to the user  $t_{HRECALL}$  delay after  $V_{CC}$  is restored to the device (see AutoStore/Power Up RECALL on page 21)

#### Interrupts

The CY14B108K has Flags register, Interrupt register, and Interrupt logic that can signal interrupt to the microcontroller. There are three potential sources for interrupt: watchdog timer, power monitor, and alarm timer. Each of these can be individually enabled to drive the INT pin by appropriate setting in the Interrupt register (0xFFFF6). In addition, each has an associated flag bit in the Flags register (0xFFFF0) that the host processor uses to determine the cause of the interrupt. The INT pin driver has two bits that specify its behavior when an interrupt occurs.

An Interrupt is raised only if both a flag is raised by one of the three sources and the respective interrupt enable bit in Interrupts register is enabled (set to '1'). After an interrupt source is active, two programmable bits, H/L and P/L, determine the behavior of the output pin driver on INT pin. These two bits are located in the Interrupt register and can be used to drive level or pulse mode

output from the INT pin. In pulse mode, the pulse width is internally fixed at approximately 200 ms. This mode is intended to reset a host microcontroller. In the level mode, the pin goes to its active polarity until the Flags register is read by the user. This mode is used as an interrupt to a host microcontroller. The control bits are summarized in the following section.

Interrupts are only generated while working on normal power and are not triggered when system is running in backup power mode.

**Note** CY14B108K generates valid interrupts only after the Powerup Recall sequence is completed. All events on INT pin must be ignored for t<sub>HRECALL</sub> duration after powerup.

### Interrupt Register

**Watchdog Interrupt Enable (WIE)**. When set to '1', the watchdog timer drives the INT pin and an internal flag when a watchdog time out occurs. When WIE is set to '0', the watchdog timer only affects the WDF flag in Flags register.

**Alarm Interrupt Enable (AIE).** When set to '1', the alarm match drives the INT pin and an internal flag. When AIE is set to '0', the alarm match only affects the AF Flags register.

**Power Fail Interrupt Enable (PFE).** When set to '1', the power fail monitor drives the pin and an internal flag. When PFE is set to '0', the power fail monitor only affects the PF flag in Flags register.

**High/Low (H/L)**. When set to a '1', the INT pin is active HIGH and the driver mode is push pull. The INT pin drives high only when  $V_{CC}$  is greater than  $V_{SWITCH}$ . When set to a '0', the INT pin is active LOW and the drive mode is open drain. The INT pin must be pulled up to Vcc by a 10k resistor while using the interrupt in active LOW mode.

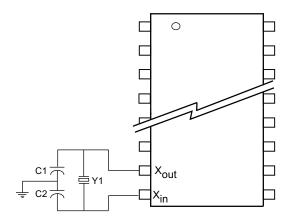
**Pulse/Level (P/L).** When set to a '1' and an interrupt occurs, the INT pin is driven for approximately 200 ms. When P/L is set to a '0', the INT pin is driven high or low (determined by H/L) until the Flags or Control register is read.

When an enabled interrupt source activates the INT pin, an external host reads the Flags registers to determine the cause. Remember that all flags are cleared when the register is read. If the INT pin is programmed for Level mode, then the condition clears and the INT pin returns to its inactive state. If the pin is programmed for Pulse mode, then reading the flag also clears the flag and the pin. The pulse does not complete its specified duration if the Flags register is read. If the INT pin is used as a host reset, the Flags register is not read during a reset

#### Flags Register

The Flag register has three flag bits: WDF, AF, and PF, which can be used to generate an interrupt. They are set by the watchdog timeout, alarm match, or power fail monitor respectively. The processor can either poll this register or enable interrupts when a flag is set. These flags are automatically reset when the register is read. The flags register is automatically loaded with the value 0x00 on power up (except for the OSCF bit. See Stopping and Starting the Oscillator on page 7)

Figure 4. RTC Recommended Component Configuration



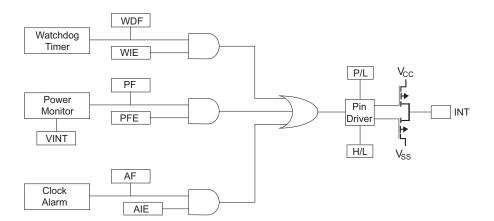
### **Recommended Values**

Y<sub>1</sub> = 32.768 KHz (12.5 pF)

 $C_1 = 12 pF$  $C_2 = 69 \text{ pF}$ 

Note: The recommended values for C1 and C2 include board trace capacitance.

Figure 5. Interrupt Block Diagram



WDF - Watchdog Timer Flag

WIE - Watchdog Interrupt

Enable

PF - Power Fail Flag

PFE - Power Fail Enable

AF - Alarm Flag

AIE - Alarm Interrupt Enable

P/L - Pulse Level

H/L - High/Low



Table 4. RTC Register  $Map^{[7]}$ 

Reg	ister			BCD Format Data <sup>[8]</sup>					Function/Pange	
CY14B108K	CY14B108M	D7	D6	D5	D4	D3	D2	D1	D0	Function/Range
0xFFFFF	0x7FFFF		10s Y	ears ears			Yea	rs		Years: 00-99
0xFFFFE	0x7FFFE	0	0	0	10s Months	Months		Months: 01–12		
0xFFFFD	0x7FFFD	0	0	10s Day	of Month		Day Of I	Month		Day of Month: 01–31
0xFFFFC	0x7FFFC	0	0	0	0	0	Da	y of wee	k	Day of week: 01–07
0xFFFFB	0x7FFFB	0	0	10s H	lours		Hou	rs		Hours: 00-23
0xFFFFA	0x7FFFA	0	1	0s Minutes			Minu	tes		Minutes: 00-59
0xFFFF9	0x7FFF9	0	10	s Seconds	3		Seco	nds		Seconds: 00-59
0xFFFF8	0x7FFF8	OSCEN (0)	0	Cal Sign (0)	Calibration (00000)				Calibration Values [9]	
0xFFFF7	0x7FFF7	WDS (0)	WDW (0)			WDT (00	00000)			Watchdog <sup>[9]</sup>
0xFFFF6	0x7FFF6	WIE (0)	AIE (0)	PFE (0)	0	H/L (1)	P/L (0)	0	0	Interrupts <sup>[9]</sup>
0xFFFF5	0x7FFF5	M (1)	0	10s Alar	m Date	n Date Alarm Day				Alarm, Day of Month: 01–31
0xFFFF4	0x7FFF4	M (1)	0	10s Alarr	m Hours		Alarm H	Hours		Alarm, Hours: 00-23
0xFFFF3	0x7FFF3	M (1)	10 A	larm Minu	tes		Alarm M	inutes		Alarm, Minutes: 00–59
0xFFFF2	0x7FFF2	M (1)	10 A	larm Seconds Alarm, Seconds			Alarm, Seconds: 00–59			
0xFFFF1	0x7FFF1		10s Ce	nturies			Centu	ries		Centuries: 00–99
0xFFFF0	0x7FFF0	WDF	AF	PF	OSCF	0	CAL (0)	W (0)	R (0)	Flags <sup>[9]</sup>

<sup>Notes
7. Upper Byte D<sub>15</sub>-D<sub>8</sub> (CY14B108M) of RTC registers are reserved for future use
8. () designates values shipped from the factory.
9. This is a binary value, not a BCD value.</sup> 



Table 5. Register Map Detail

Reg	ister				Dosor	intion						
CY14B108K	CY14B108M	- Description										
	A =====				Time Keep	ing - Years						
0xFFFFF	0x7FFFF	D7	D6	D5	D4	D3	D2	D1 Day of Week eek. Day of the we	D0			
			10s	Years	<u> </u>		Ye	ears				
		upper nibb		contains the								
			Time Keeping - Months									
0xFFFFE	0x7FFFE	D7	D6	D5	D4	D3	D2	D1	D0			
		0	0	0	10s Month		Mo	nths				
		from 0 to 9		ole (one bit) c	ontains the u	pper digit ár						
0xFFFFD	0x7FFFD				Time Keep							
	OX	D7	D6	D5	D4	D3	D2		D0			
		0	0	10s Day	of Month		Day o	f Month				
0xFFFFC	0x7FFFC	and operates from 0 to 9; upper nibble (two bits) contains the 10s digit and operates from 0 to 3. The range for the register is 1–31. Leap years are automatically adjusted for.  Time Keeping - Day										
OXI I I I O	OX/1110	D7	D6	D5	D4	D3	D2	D1	D0			
		0	0	0	0	0		Day of Wee	k			
		ring count	er that count		then returns	to 1. The us						
0xFFFFB	0x7FFFB	Time Keeping - Hours										
UXFFFFB	UX/FFFB	D7	D6	D5	D4	D3	D2	D1	D0			
		0	0	10s	Hours		Н	ours				
		digit and o	perates fron	ue of hours in n 0 to 9; uppe ne register is	r nibble (two							
0xFFFFA	0x7FFFA				Time Keepir	ng - Minutes	5					
VXFFFFA	UX/FFFA	D7	D6	D5	D4	D3	D2	D1	D0			
		0		10s Minutes			Mir	nutes				
		from 0 to 9	); upper nibb	ie of minutes. ble (three bits ster is 0–59.								
OVEEEEO	0.75550			•	Гime Keepin	g - Second	S					
0xFFFF9	0x7FFF9	D7	D6	D5	D4	D3	D2	D1	D0			
	1	0		10s Second	3		Sec	conds				
		from 0 to 9		e of seconds le (three bits)								



Table 5. Register Map Detail (continued)

Reg	ister				Descri	ntion					
CY14B108K	CY14B108M				Descri	puon					
Overero	0×7550	Calibration/Control									
0xFFFF8	0x7FFF8	D7	D6	D5	D4	D3	D2	D1	D0		
	ı	OSCEN	0	Calibration		l .	Calibration	l .			
				Sign							
OSC	CEN			en set to 1, the saves batter				), the oscilla	tor runs.		
Calib	ration			ation adjustm	•		•	aa a subtraa	tion (0) from		
	gn	the time-ba		alion aujusiii	ierit is applied	i as aii auuili	1011 (1) 10 01 6	as a subilac	uon (o) noi		
Calibration		These five bits control the calibration of the clock.									
					WatchDo	g Timer					
0xFFFF7	0x7FFF7	D7	D6	D5	D4	D3	D2	D1	D0		
	L	WDS	WDW			WE	WDT s the watchdog timer. Setting the b watchdog timer is reset. The WDS b				
WI	DS	0 has no e	ffect. The bit	ing this bit to is cleared au llways returns	itomatically a	d restarts th fter the wato	e watchdog chdog timer	timer. Settii is reset. The	ng the bit to WDS bit i		
WI	DW	(D5–D0). Setting this	Watchdog Write Enable. Setting this bit to 1 disables any WRITE to the watchdog timeout value (D5–D0). This allows the user to set the watchdog strobe bit without disturbing the timeout value. Setting this bit to 0 allows bits D5–D0 to be written to the watchdog register when the next write cycle is complete. This function is explained in more detail in Watchdog Timer on page 8.								
W	DT	Watchdog timeout selection. The watchdog timer interval is selected by the 6-bit value in this register. It represents a multiplier of the 32 Hz count (31.25 ms). The range of timeout value is 31.25 ms (a setting of 1) to 2 seconds (setting of 3 Fh). Setting the watchdog timer register to 0 disables the timer. These bits can be written only if the WDW bit was set to 0 on a previous cycle.									
OVEEEE	075556	Interrupt Status/Control									
0xFFFF6	0x7FFF6	D7	D6	D5	D4	D3	D2	D1	D0		
	I .	WIE	AIE	PFE	0	H/L	P/L	0	0		
W	ΊΕ	Watchdog Interrupt Enable. When set to 1 and a watchdog timeout occurs, the watchdog timer drives the INT pin and the WDF flag. When set to 0, the watchdog timeout affects only the WDF flag.									
Α	IE	Alarm Interrupt Enable. When set to 1, the alarm match drives the INT pin and the AF flag. When set to 0, the alarm match only affects the AF flag.									
Pi	E	Power Fail Enable. When set to 1, the power fail monitor drives the INT pin and the PF flag. When set to 0, the power fail monitor affects only the PF flag.									
(	)	Reserved for future use									
Н	/L	High/Low. When set to 1, the INT pin is driven active HIGH. When set to 0, the INT pin is open drain, active LOW.									
Р	/L	Pulse/Level. When set to 1, the INT pin is driven active (determined by H/L) by an interrupt source for approximately 200 ms. When set to 0, the INT pin is driven to an active level (as set by H/L) until the flags register is read.									
0xFFFF5	0x7FFF5				Alarm	- Day					
JA V	OX. 1110	D7	D6	D5	D4	D3	D2	D1	D0		
		М	0		rm Date			n Date			
		Contains to value.	he alarm val	ue for the date	e of the month	h and the ma	ask bit to sel	lect or desel	ect the dat		
N	И		Match. When this bit is set to 0, the date value is used in the alarm match. Setting this bit to 1 causes the match circuit to ignore the date value.								



Table 5. Register Map Detail (continued)

Register					Descr	intion						
CY14B108K	CY14B108M	- Description										
0xFFFF4	0x7FFF4		Alarm - Hours									
UXFFFF4	UX/FFF4	D7	D6	D5	D4	D3	D2	D1	D0			
		М	1	0s Alarm Ho	urs		Alarm	Hours	I.			
		Contains th	ne alarm va	lue for the ho	urs and the r	nask bit to s	elect or des	elect the ho	urs value.			
N	M			s set to 0, the uit to ignore t			e alarm mat	tch. Setting	this bit to 1			
0xFFFF3 0x7FFF3		Alarm - Minutes										
UXFFFF3	UX/FFF3	D7	D6	D5	D4	D3	D2	D1	D0			
	1	М	10	s Alarm Min	ıtes		Alarm	Minutes	I			
		Contains th	ne alarm val	ue for the mir	utes and the	mask bit to	select or des	select the mi	nutes valu			
N	M			set to 0, the uit to ignore t			the alarm ma	atch. Setting	this bit to			
0vEEEE2	0×7555				Alarm - S	Seconds						
0xFFFF2	0x7FFF2	D7	D6	D5	D4	D3	D2	D1	D0			
		М	10	s Alarm Seco	onds		Alarm	Seconds	Į.			
		Contains th	ne alarm val	ue for the sec	onds and the	mask bit to s	elect or des	elect the sec	onds' valu			
N	M	Match. When this bit is set to 0, the seconds value is used in the alarm match. Setting this bit to 1 causes the match circuit to ignore the seconds value.										
0.455554	075554	Time Keeping - Centuries										
0xFFFF1	0x7FFF1	D7	D6	D5	D4	D3	D2	D1	D0			
		10s Centuries Centuries						I				
		Contains the BCD value of centuries. Lower nibble contains the lower digit and operates from 0 to 9; upper nibble contains the upper digit and operates from 0 to 9. The range for the register is 0-99 centuries.										
0 55550	0.75550	Flags										
0xFFFF0	0x7FFF0	D7	D6	D5	D4	D3	D2	D1	D0			
	<u> </u>	WDF	AF	PF	OSCF	0	CAL	W	R			
W	DF	Watchdog Timer Flag. This read only bit is set to 1 when the watchdog timer is allowed to reach 0 without being reset by the user. It is cleared to 0 when the Flags register is read or on power up										
A	F	Alarm Flag. This read only bit is set to 1 when the time and date match the values stored in the alarm registers with the match bits = 0. It is cleared when the Flags register is read or on power u										
Р	F	Power Fail Flag. This read only bit is set to 1 when power falls below the power fail threshold V <sub>SWITCH</sub> . It is cleared to 0 when the Flags register is read or on power up.										
OS	SCF	Oscillator Fail Flag. Set to 1 on power up if the oscillator is enabled and not running in the first 5 ms of operation. This indicates that RTC backup power failed and clock value is no longer valid. This bit survives power cycle and is never cleared internally by the chip. The user must check for this condition and write '0' to clear this flag.										
C	AL	Calibration Mode. When set to 1, a 512 Hz square wave is output on the INT pin. When set to 0, the INT pin resumes normal operation. This bit defaults to 0 (disabled) on power up.										
V	V	Write Enab to RTC reg the W bit to	ole: Setting t isters, Alarn o 0 causes	he W bit to 1 in registers, Cathe contents of changed (a n	reezes updated in the contraction region in the RTC re	tes of the RT ister, Interrup gisters to be	C registers. ot register ar e transferred	The user cand Flags reging to the time	n then wri ster. Settir keeping			
F	₹	are not see	en during th	R bit to 1, sto e reading pro it does not re	cess. Set R I	oit to 0 to res	sume clock i	updates to the	ne holding			



# **Maximum Ratings**

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested. $ \begin{tabular}{ll} \hline \end{tabular} $
Storage Temperature–65°C to +150°C
Maximum Accumulated Storage Time
At 150°C Ambient Temperature 1000h
At 85°C Ambient Temperature
Ambient Temperature with Power Applied –55°C to +150°C
Supply Voltage on V <sub>CC</sub> Relative to GND0.5V to 4.1V
Voltage Applied to Outputs in High Z State–0.5V to $V_{\rm CC}$ + 0.5V
Input Voltage0.5V to Vcc + 0.5V
Transient Voltage (<20 ns) on Any Pin to Ground Potential–2.0V to $V_{\rm CC}$ + 2.0V

Package Power Dissipation Capability (T <sub>A</sub> = 25°C)	1.0W
Surface Mount Pb Soldering Temperature (3 Seconds)	
DC Output Current (1 output at a time, 1s dur	
Static Discharge Voltage(per MIL-STD-883, Method 3015)	> 2001V
Latch Up Current	> 200 mA

# **Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>
Commercial	0°C to +70°C	2.7V to 3.6V
Industrial	–40°C to +85°C	

### **DC Electrical Characteristics**

Over the Operating Range ( $V_{CC} = 2.7V \text{ to } 3.6V$ )

Parameter	Description	Test Conditions	Min	<b>Typ</b> <sup>[10]</sup>	Max	Unit	
$V_{CC}$	Power Supply			2.7	3.0	3.6	V
I <sub>CC1</sub>	Average V <sub>CC</sub> Current	$t_{RC}$ = 25 ns $t_{RC}$ = 45 ns	Commercial			70 70 55	mA mA mA
	Values obtained without output loads (I <sub>OUT</sub> = 0 mA)	Industrial			75 75 57	mA mA mA	
I <sub>CC2</sub>	Average V <sub>CC</sub> Current during STORE	All Inputs Don't Care, V <sub>CC</sub> = Max. Average current for duration t <sub>STORE</sub>				20	mA
I <sub>CC3</sub>	Average $V_{CC}$ Current at $t_{RC}$ = 200 ns, $V_{CC}$ (Typ), 25°C	All Inputs Cycling at CMOS Levels. Values obtained without output loads (I <sub>OUT</sub> = 0	mA).		40		mA
I <sub>CC4</sub>	Average V <sub>CAP</sub> Current during AutoStore Cycle	All Inputs Don't Care. Average current for durat	tion t <sub>STORE</sub>			10	mA
I <sub>SB</sub>	V <sub>CC</sub> Standby Current	CE $\geq$ (V <sub>CC</sub> - 0.2V). V <sub>IN</sub> $\leq$ 0.2V or $\geq$ (V <sub>CC</sub> - 0.2V) Standby current level after nonvolatile cycle is a linputs are static. f = 0 MHz.	/). complete.			10	mA
I <sub>IX</sub> <sup>[11]</sup>	Input Leakage Current (except HSB)	$V_{CC} = Max, V_{SS} \le V_{IN} \le V_{CC}$		-2		+2	μА
	Input Leakage Current (for HSB)	$V_{CC} = Max, V_{SS} \le V_{IN} \le V_{CC}$		-200		+2	μΑ
I <sub>OZ</sub>	Off State Output Leakage Current	$V_{CC} = Max, V_{SS} \le V_{OUT} \le V_{CC}, \overline{CE} \text{ or } \overline{OE} \ge V_{IH}$ $\ge V_{IH} \text{ or } \overline{WE} \le V_{IL}$	or BHE/BLE	-2		+2	μА
V <sub>IH</sub>	Input HIGH Voltage			2.0		$V_{CC} + 0.5$	V
$V_{IL}$	Input LOW Voltage			$V_{ss} - 0.5$		0.8	V
V <sub>OH</sub>	Output HIGH Voltage			2.4			V
$V_{OL}$	Output LOW Voltage					0.4	V
$V_{CAP}$	Storage Capacitor	Between V <sub>CAP</sub> pin and V <sub>SS</sub> , 5V Rated		122	150	360	μF

#### Notes

 <sup>10.</sup> Typical values are at 25°C, V<sub>CC</sub>= V<sub>CC</sub> (Typ). Not 100% tested.
 11. The HSB pin has I<sub>OUT</sub> = -2 uA for V<sub>OH</sub> of 2.4V when both active HIGH and LOW drivers are disabled. When they are enabled standard V<sub>OH</sub> and V<sub>OL</sub> are valid. This parameter is characterized but not tested.



# **Data Retention and Endurance**

Parameter	Description	Min	Unit
DATA <sub>R</sub>	Data Retention	20	Years
NV <sub>C</sub>	Nonvolatile STORE Operations	200	К

# Capacitance

In the following table, the capacitance parameters are listed. <sup>[12]</sup>

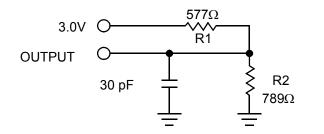
Parameter	Description	Test Conditions	Max	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	14	pF
C <sub>OUT</sub>	Output Capacitance	$V_{CC} = V_{CC}$ (Typ)	14	pF

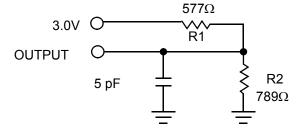
### **Thermal Resistance**

In the following table, the thermal resistance parameters are listed. [12]

Parameter	Description	Test Conditions	44 TSOP II	54 TSOP II	Unit
$\Theta_{JA}$	Thermal Resistance (Junction to Ambient)	Test conditions follow standard test methods and procedures for	31.11	30.73	°C/W
$\Theta_{JC}$	Thermal Resistance (Junction to Case)	measuring thermal impedance, in accordance with EIA/JESD51.	5.56	6.08	°C/W

Figure 6. AC Test Loads





### **AC Test Conditions**

Input Pulse Levels	V to 3V
Input Rise and Fall Times (10% - 90%)	<u>&lt;</u> 3 ns
Input and Output Timing Reference Levels	1.5V

#### Note

<sup>12.</sup> These parameters are only guaranteed by design and are not tested.



### **RTC Characteristics**

Parameters	Description		Min	<b>Typ</b> <sup>[10]</sup>	Max	Units
V <sub>RTCbat</sub>	RTC Battery Pin Voltage		1.8	3.0	3.3	V
I <sub>BAK</sub> <sup>[13]</sup>	RTC Backup Current	T <sub>A</sub> (Min)			350	nA
		25°C		350		nA
		T <sub>A</sub> (Max)			500	nA
V <sub>RTCcap</sub> <sup>[14]</sup>	RTC Capacitor Pin Voltage	T <sub>A</sub> (Min)	1.6	3.0	3.6	V
		25°C	1.5	3.0	3.6	V
		T <sub>A</sub> (Max)	1.4	3.0	3.6	V
tOCS	RTC Oscillator Time to Start			1	2	sec
R <sub>BKCHG</sub>	RTC Backup Capacitor Charge Current -Limiting Resistor		450		850	Ω

Notes
 13. From either V<sub>RTCcap</sub> or V<sub>RTCbat</sub>.
 14. If V<sub>RTCcap</sub> > 0.3V or if no capacitor is connected to V<sub>RTCcap</sub> pin, the oscillator starts in tOCS time. If a backup capacitor is connected and vrtccap < 0.3V, the capacitor must be allowed to charge to 0.3V for oscillator to start.</li>

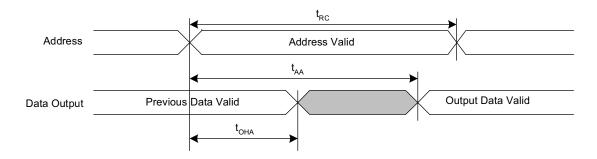


# **AC Switching Characteristics**

Param	neters		20	ns	25 ns		45 ns		
Cypress Parameters	Alt Parameters	Description	Min	Max	Min	Max	Min	Max	Unit
SRAM Read Cy	cle		•		•				
t <sub>ACE</sub>	t <sub>ACS</sub>	Chip Enable Access Time		20		25		45	ns
t <sub>RC</sub> <sup>[15]</sup>	t <sub>RC</sub>	Read Cycle Time	20		25		45		ns
t <sub>AA</sub> <sup>[16]</sup>	t <sub>AA</sub>	Address Access Time		20		25		45	ns
t <sub>DOE</sub>	t <sub>OE</sub>	Output Enable to Data Valid		10		12		20	ns
t <sub>OHA</sub> <sup>[16]</sup>	t <sub>OH</sub>	Output Hold After Address Change	3		3		3		ns
t <sub>LZCE</sub> [12, 17]	t <sub>LZ</sub>	Chip Enable to Output Active	3		3		3		ns
t <sub>HZCE</sub> [12, 17]	t <sub>HZ</sub>	Chip Disable to Output Inactive		8		10		15	ns
t <sub>1.70F</sub> [12, 17]	t <sub>OLZ</sub>	Output Enable to Output Active	0		0		0		ns
t <sub>HZOE</sub> [12, 17]	t <sub>OHZ</sub>	Output Disable to Output Inactive		8		10		15	ns
t <sub>PU</sub> [12]	t <sub>PA</sub>	Chip Enable to Power Active	0		0		0		ns
t <sub>PD</sub> <sup>[12]</sup>	t <sub>PS</sub>	Chip Disable to Power Standby		20		25		45	ns
t <sub>DBE</sub>	-	Byte Enable to Data Valid		10		12		20	ns
t <sub>LZBE</sub> <sup>[12]</sup>	-	Byte Enable to Output Active	0		0		0		ns
t <sub>HZBE</sub> <sup>[12]</sup>	-	Byte Disable to Output Inactive		8		10		15	ns
SRAM Write Cy	cle		•		•				•
t <sub>WC</sub>	t <sub>WC</sub>	Write Cycle Time	20		25		45		ns
t <sub>PWE</sub>	t <sub>WP</sub>	Write Pulse Width	15		20		30		ns
t <sub>SCE</sub>	t <sub>CW</sub>	Chip Enable To End of Write	15		20		30		ns
t <sub>SD</sub>	t <sub>DW</sub>	Data Setup to End of Write	8		10		15		ns
t <sub>HD</sub>	t <sub>DH</sub>	Data Hold After End of Write	0		0		0		ns
t <sub>AW</sub>	t <sub>AW</sub>	Address Setup to End of Write	15		20		30		ns
t <sub>SA</sub>	t <sub>AS</sub>	Address Setup to Start of Write	0		0		0		ns
t <sub>HA</sub>	t <sub>WR</sub>	Address Hold After End of Write	0		0		0		ns
t <sub>HZWE</sub> [12, 17,18]	t <sub>WZ</sub>	Write Enable to Output Disable		8		10		15	ns
t <sub>LZWE</sub> [12, 17]	t <sub>OW</sub>	Output Active after End of Write	3		3		3		ns
t <sub>BW</sub>	-	Byte Enable to End of Write	15		20		30		ns

# **Switching Waveforms**

Figure 7. SRAM Read Cycle 1: Address Controlled<sup>[15, 16, 19]</sup>



- 15. WE must be HIGH during SRAM read cycles.

  16. Device is continuously selected with CE, OE and BHE / BLE LOW.

  17. Measured ±200 mV from steady state output voltage.

  18. If WE is LOW when CE goes LOW, the outputs remain in the high impedance state.

  19. HSB must remain HIGH during Read and Write cycles.



# **Switching Waveforms**

Figure 8. SRAM Read Cycle 2:  $\overline{\text{CE}}$  and  $\overline{\text{OE}}$  Controlled<sup>[3, 15, 19]</sup>

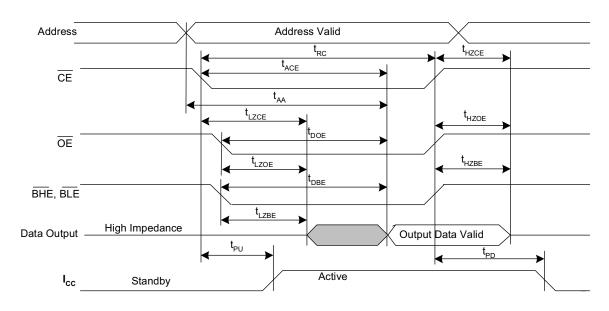
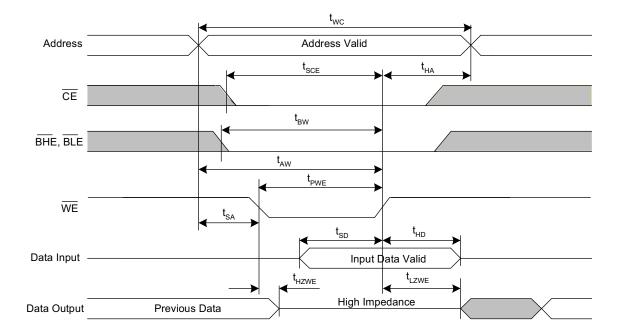


Figure 9. SRAM Write Cycle 1:  $\overline{\text{WE}}$  Controlled<sup>[3, 18, 19, 20]</sup>



Note

20. CE or WE must be ≥V<sub>IH</sub> during address transitions.



# **Switching Waveforms**

Figure 10. SRAM Write Cycle 2:  $\overline{\text{CE}}$  Controlled<sup>[3, 18, 19, 20]</sup>

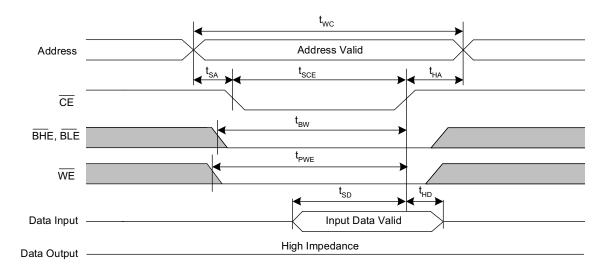
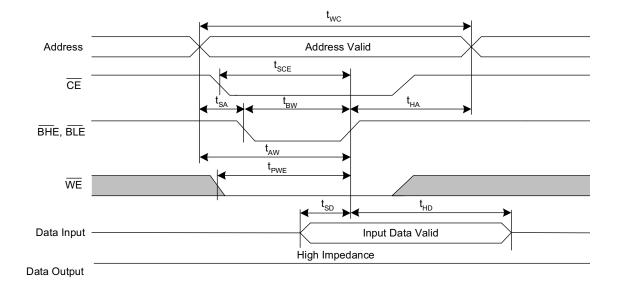


Figure 11. SRAM Write Cycle 3: BHE and BLE Controlled<sup>[5, 18, 19, 20, 21]</sup>
(Not applicable for RTC register writes)



21. Only  $\overline{\text{CE}}$  and  $\overline{\text{WE}}$  controlled writes to RTC registers are allowed.  $\overline{\text{BLE}}$  pin must be held LOW before  $\overline{\text{CE}}$  or  $\overline{\text{WE}}$  pin goes LOW for writes to RTC register.

Note

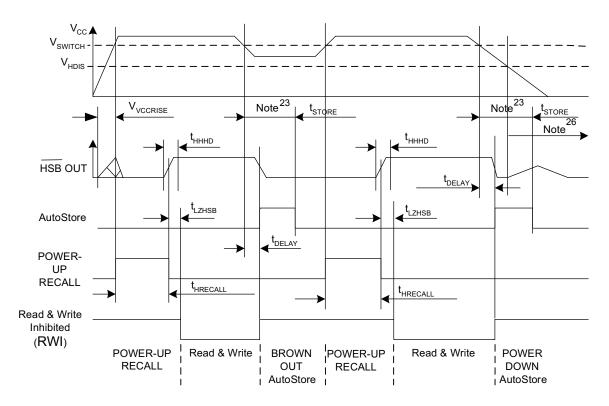


# **AutoStore/Power Up RECALL**

Parameters	Description	20 ns		25 ns		45 ns		Unit
rarameters	Description	Min	Max	Min	Max	Min	Max	Ullit
t <sub>HRECALL</sub> [22]	Power Up RECALL Duration		20		20		20	ms
t <sub>STORE</sub> [23]	STORE Cycle Duration		8		8		8	ms
t <sub>DELAY</sub> [24]	Time Allowed to Complete SRAM Write Cycle		20		25		25	ns
V <sub>SWITCH</sub>	Low Voltage Trigger Level		2.65		2.65		2.65	V
t <sub>VCCRISE</sub> <sup>[12]</sup>	V <sub>CC</sub> Rise Time	150		150		150		μS
V <sub>HDIS</sub> <sup>[12]</sup>	HSB Output Disable Voltage		1.9		1.9		1.9	V
t <sub>LZHSB</sub> <sup>[12]</sup>	HSB To Output Active Time		5		5		5	μS
t <sub>HHHD</sub> <sup>[12]</sup>	HSB High Active Time		500		500		500	ns

# **Switching Waveforms**

Figure 12. AutoStore or Power Up RECALL<sup>[25]</sup>



#### Notes

- 22. t<sub>HRECALL</sub> starts from the time V<sub>CC</sub> rises above V<sub>SWITCH</sub>.
  23. If an SRAM write has not taken place since the last nonvolatile cycle, no AutoStore or Hardware STORE takes place.
  24. On a Hardware Store and AutoStore initiation, SRAM write operation continues to be enabled for time t<sub>DELAY</sub>.
  25. <u>Read</u> and Write cycles are ignored during STORE, RECALL, and while V<sub>CC</sub> is below V<sub>SWITCH</sub>.
  26. HSB pin is driven HIGH to V<sub>CC</sub> only by internal 100 kΩ resistor, HSB driver is disabled.



# **Software Controlled STORE and RECALL Cycle**

In the following table, the software controlled STORE and RECALL cycle parameters are listed. [27, 28]

Parameters	Description	20 ns		25 ns		45 ns		Unit
raiailleteis	Description	Min	Max	Min	Max	Min	Max	Offic
t <sub>RC</sub>	STORE/RECALL Initiation Cycle Time	20		25		45		ns
t <sub>SA</sub>	Address Setup Time	0		0		0		ns
t <sub>CW</sub>	Clock Pulse Width	15		20		30		ns
t <sub>HA</sub>	Address Hold Time	0		0		0		ns
t <sub>RECALL</sub>	RECALL Duration		200		200		200	μS
t <sub>SS</sub> [32, 33]	Soft Sequence Processing Time		100		100		100	μS

# **Switching Waveforms**

Figure 13. CE and OE Controlled Software STORE and RECALL Cycle<sup>[28]</sup>

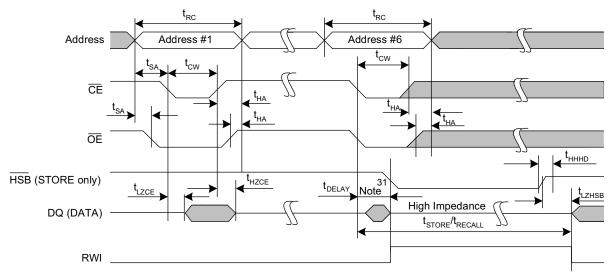
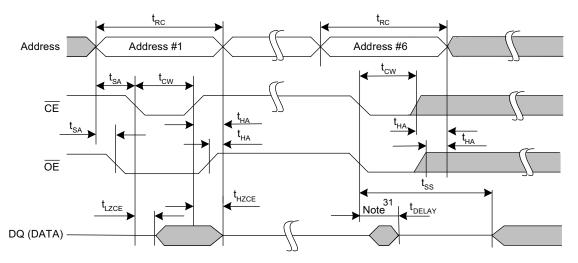


Figure 14. AutoStore Enable and Disable Cycle



#### Notes

- 27. The software sequence is clocked with  $\overline{\text{CE}}$  controlled or  $\overline{\text{OE}}$  controlled reads.

  28. The six consecutive addresses must be read in the order listed in Table 2.  $\overline{\text{WE}}$  must be HIGH during all six consecutive cycles.
- 29. This is the amount of time it takes to take action on a soft sequence command. Vcc power must remain HIGH to effectively register command. 30. Commands such as STORE and RECALL lock out I/O until operation is complete which further increases this time. See the specific command.
- 31. DQ output data at the sixth read may be invalid since the output is disabled at t<sub>DELAY</sub> time.



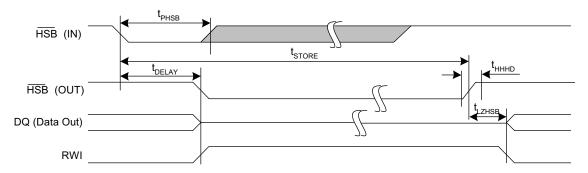
# **Hardware STORE Cycle**

Parameters	Description	20 ns		25 ns		45 ns		Unit
raiailleteis	Description	Min	Max	Min	Max	Min	Max	Oilit
t <sub>DHSB</sub>	HSB To Output Active Time when write latch not set		20		25		25	ns
t <sub>PHSB</sub>	Hardware STORE Pulse Width	15		15		15		ns

# **Switching Waveforms**

Figure 15. Hardware STORE Cycle<sup>[23]</sup>

### Write latch set



### Write latch not set

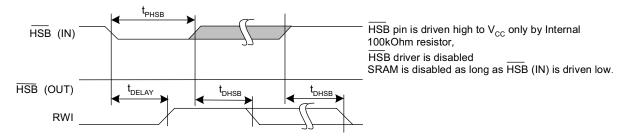
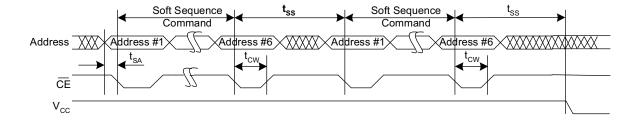


Figure 16. Soft Sequence Processing<sup>[32, 33]</sup>



<sup>32.</sup> This is the amount of time it takes to take action on a soft sequence command. Vcc power must remain HIGH to effectively register command. 33. Commands such as STORE and RECALL lock out I/O until operation is complete which further increases this time. See the specific command.



# **Truth Table For SRAM Operations**

HSB should remain HIGH for SRAM Operations.

# For x8 Configuration

CE	WE	OE	Inputs and Outputs <sup>[2]</sup>	Mode	Power
Н	Х	Х	High Z	Deselect/Power Down	Standby
L	Н	L	Data Out (DQ <sub>0</sub> –DQ <sub>7</sub> );	Read	Active
L	Н	Н	High Z	Output Disabled	Active
L	L	Х	Data in (DQ <sub>0</sub> –DQ <sub>7</sub> );	Write	Active

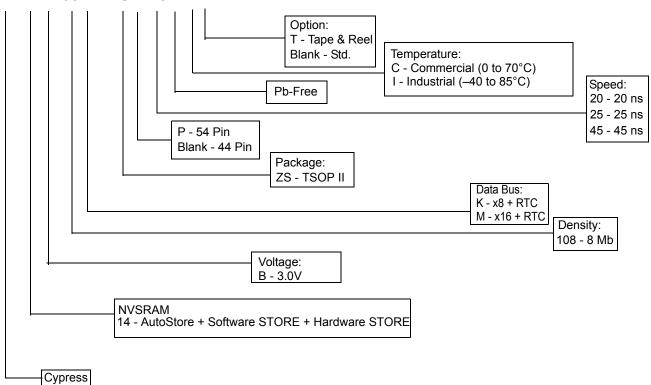
# For x16 Configuration

CE	WE	OE	BHE <sup>[3]</sup>	BLE <sup>[3]</sup>	Inputs and Outputs <sup>[2]</sup>	Mode	Power
Н	Х	Х	Х	X	High Z	Deselect/Power Down	Standby
L	Х	Х	Н	Η	High Z	Output Disabled	Active
L	Н	L	L	L	Data Out (DQ <sub>0</sub> –DQ <sub>15</sub> )	Read	Active
L	Н	L	Н	L	Data Out (DQ <sub>0</sub> –DQ <sub>7</sub> ); DQ <sub>8</sub> –DQ <sub>15</sub> in High Z	Read	Active
L	Н	L	L	Н	Data Out (DQ <sub>8</sub> –DQ <sub>15</sub> ); DQ <sub>0</sub> –DQ <sub>7</sub> in High Z	Read	Active
L	Н	Н	L	L	High Z	Output Disabled	Active
L	Н	Н	Н	L	High Z	Output Disabled	Active
L	Н	Н	L	Н	High Z	Output Disabled	Active
L	L	Х	L	L	Data In (DQ <sub>0</sub> –DQ <sub>15</sub> )	Write	Active
L	L	Х	Н	L	Data In (DQ <sub>0</sub> –DQ <sub>7</sub> ); DQ <sub>8</sub> –DQ <sub>15</sub> in High Z	Write	Active
L	L	Х	L	Н	Data In (DQ <sub>8</sub> –DQ <sub>15</sub> ); DQ <sub>0</sub> –DQ <sub>7</sub> in High Z	Write	Active



# **Part Numbering Nomenclature**

# CY14 B 108 K - ZS P 20 X C T





# **Ordering Information**

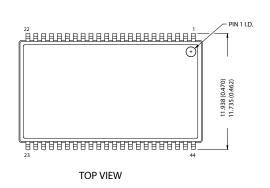
Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
20	CY14B108K-ZS20XCT	51-85087	44-pin TSOPII	Commercial
	CY14B108K-ZS20XC	51-85087	44-pin TSOPII	
	CY14B108K-ZS20XIT	51-85087	44-pin TSOPII	Industrial
	CY14B108K-ZS20XI	51-85087	44-pin TSOPII	
	CY14B108M-ZSP20XCT	51-85160	54-pin TSOPII	Commercial
	CY14B108M-ZSP20XC	51-85160	54-pin TSOPII	
	CY14B108M-ZSP20XIT	51-85160	54-pin TSOPII	Industrial
	CY14B108M-ZSP20XI	51-85160	54-pin TSOPII	
25	CY14B108K-ZS25XCT	51-85087	44-pin TSOPII	Commercial
	CY14B108K-ZS25XC	51-85087	44-pin TSOPII	
	CY14B108K-ZS25XIT	51-85087	44-pin TSOPII	Industrial
	CY14B108K-ZS25XI	51-85187	44-pin TSOPII	
	CY14B108M-ZSP25XCT	51-85160	54-pin TSOPII	Commercial
	CY14B108M-ZSP25XC	51-85160	54-pin TSOPII	
	CY14B108M-ZSP25XIT	51-85160	54-pin TSOPII	Industrial
	CY14B108M-ZSP25XI	51-85160	54-pin TSOPII	
45	CY14B108K-ZS45XCT	51-85087	44-pin TSOPII	Commercial
	CY14B108K-ZS45XC	51-85087	44-pin TSOPII	
	CY14B108K-ZS45XIT	51-85087	44-pin TSOPII	Industrial
	CY14B108K-ZS45XI	51-85187	44-pin TSOPII	
	CY14B108M-ZSP45XCT	51-85160	54-pin TSOPII	Commercial
	CY14B108M-ZSP45XC	51-85160	54-pin TSOPII	
	CY14B108M-ZSP45XIT	51-85160	54-pin TSOPII	Industrial
	CY14B108M-ZSP45XI	51-85160	54-pin TSOPII	

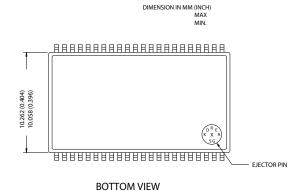
All the above parts are Pb-free.

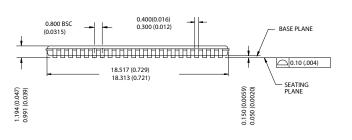


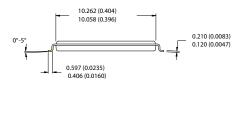
# **Package Diagrams**

Figure 17. 44-Pin TSOP II (51-85087)







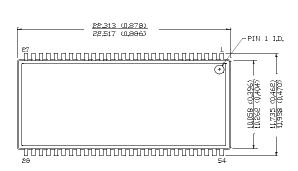


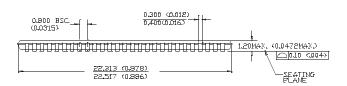
51-85087 \*A

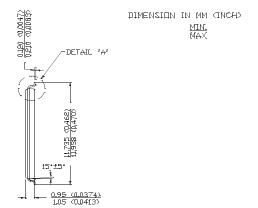


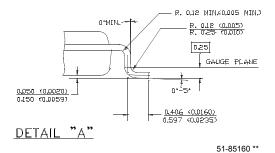
# Package Diagrams (continued)

Figure 18. 54-Pin TSOP II (51-85160)











## **Document History Page**

Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
**	2681767	GVCH/PYRS	04/01/09	New Data Sheet
*A	2712462	GVCH/PYRS	05/29/2009	Moved data sheet status from Preliminary to Final Updated AutoStore operation Updated C1, C2 values to 12pF, 69pF from 21pF, 21pF respectively Updated I <sub>SB</sub> test condition Updated footnote 10 Updated I <sub>BAK</sub> and V <sub>RTCcap</sub> parameter values Added R <sub>BKCHG</sub> parameter to RTC characteristics table Added footnote 14 Referenced footnote 12 to V <sub>CCRISE</sub> , t <sub>HHHD</sub> and t <sub>LZHSB</sub> parameters Updated V <sub>HDIS</sub> parameter description
*B	2746310	GVCH	07/29/2009	Page 4: Updated Hardware STORE (HSB) operation description page 4: Updated Software STORE description Updated t <sub>DELAY</sub> parameter description Updated footnote 24 and added footnote 31 Referenced footnote 31 to Figure 11 and Figure 12

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Revised July 30, 2009

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